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## Electronic Supplementary Materials

to

### ***Operando* Exploration of Tribochemical Decomposition in Synthetic FeS<sub>2</sub> thin film and Mineral Iron Pyrite**

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#### 1. XRD of thin film and mineral pyrite

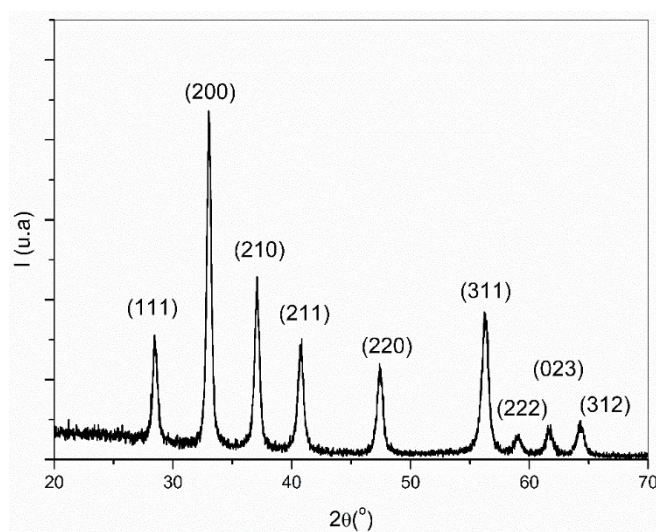


Fig. S1. Grazing-angle X-ray diffraction spectrum of obtained FeS<sub>2</sub> thin film. The corresponding crystal planes of iron pyrite are shown at each peak.

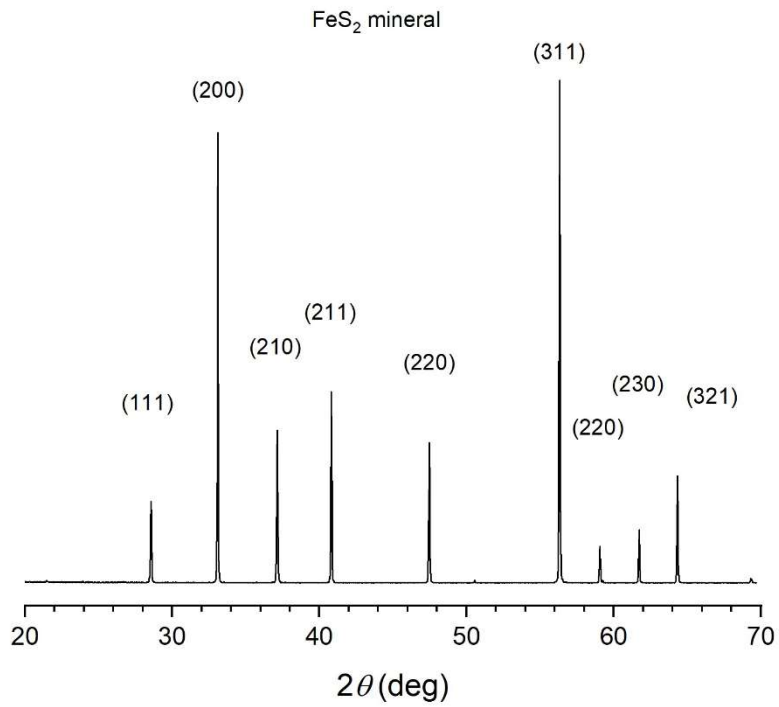


Fig. S2. X-ray diffraction patterns of mineral pyrite.

The XRD diagram of mineral pyrite shown in Fig. S2 perfectly matches the standard one (JCPDS No. 01-071-0053). The diagram of a thin-film sample shows all the main reflexes of mineral pyrite, but the relative intensities are slightly different. Furthermore, broadening of the peaks suggest a higher defect density and/or smaller grain size in the thin film.

## 2. Rutherford Backscattering Spectroscopy (RBS) and Elastic Recoil Detection Analysis (ERDA)

The samples were analyzed with RBS and ERDA methods (at  $170^\circ$  and  $30^\circ$  scattering angles, respectively) using two Si detectors (fixed and movable detector) simultaneously.

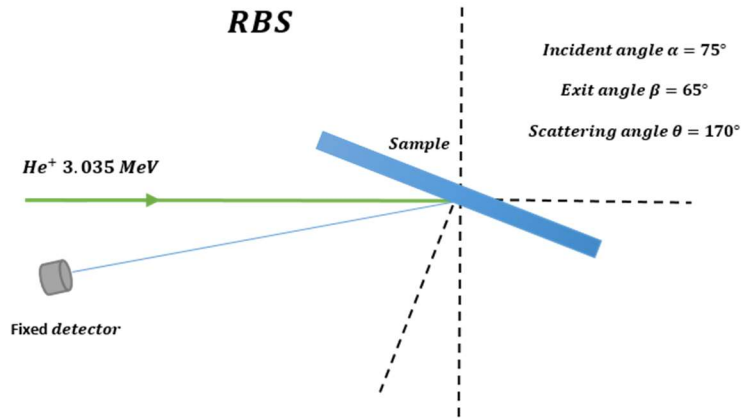


Fig. S3. Configuration of the RBS experiments under **O-resonance conditions** (3.035 MeV  $He^+$  beam)

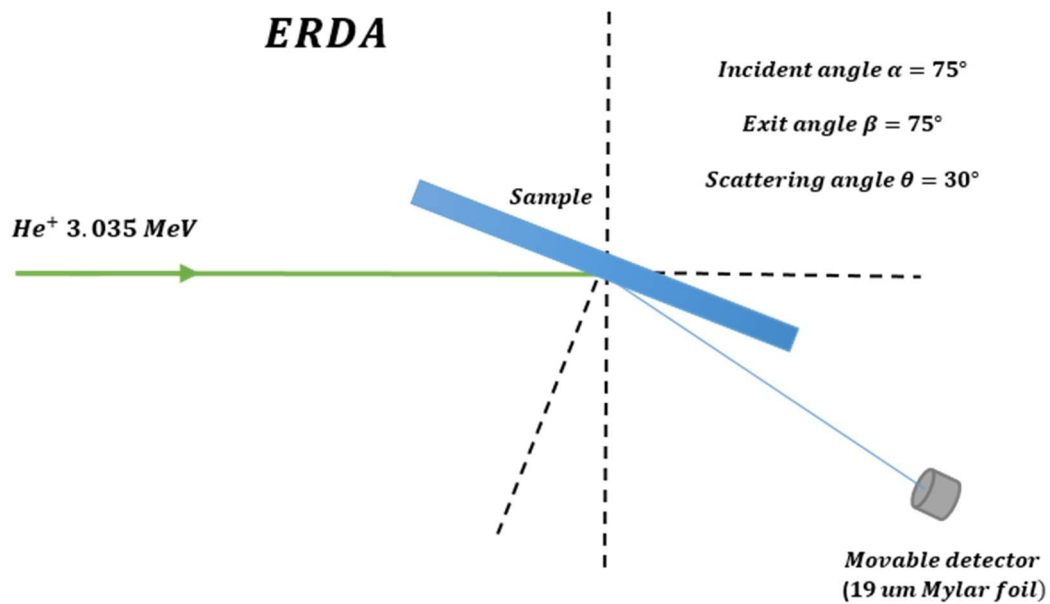


Fig. S4. Configuration of the ERDA experiments under **O-resonance conditions** (3.035 MeV  $He^+$  beam)

The following figures show the experimentally measured data and fitting results, which were obtained using the calibration values 11.45 keV of energy offset and 2.23 keV of energy per channel.

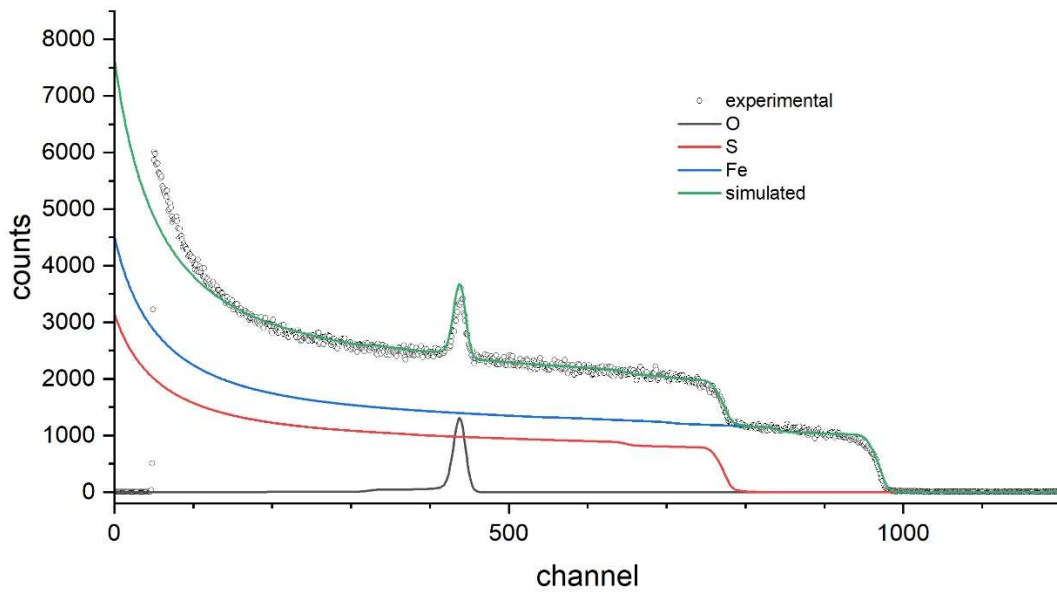


Fig. S5. RBS data and fitting results for mineral pyrite obtained under O-resonance conditions.

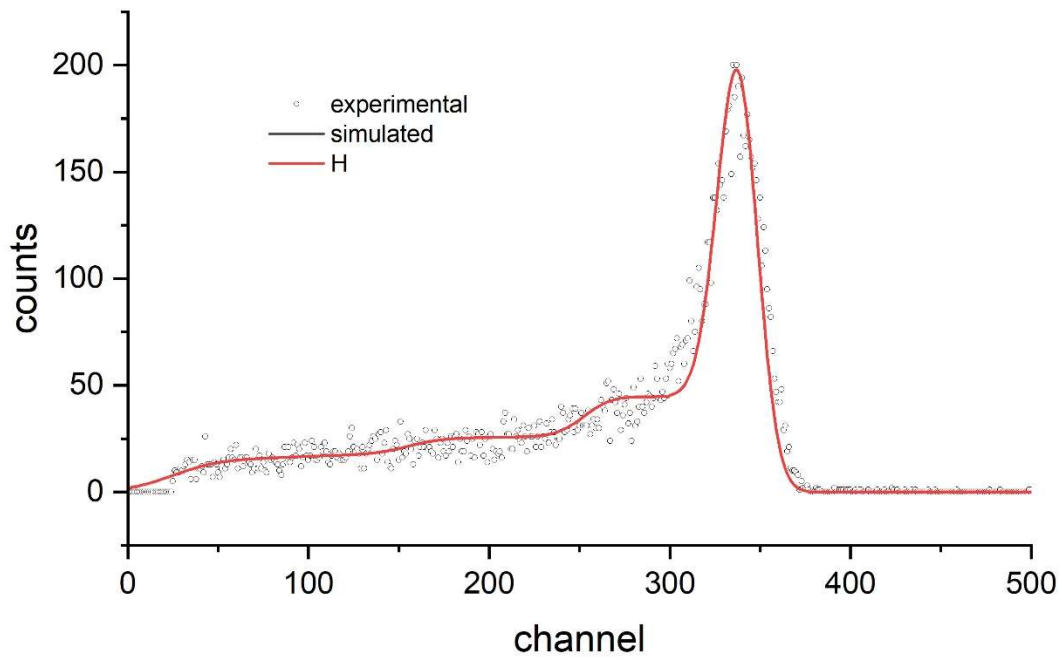


Fig. S6. ERDA data and fitting results for mineral pyrite obtained under O-resonance conditions

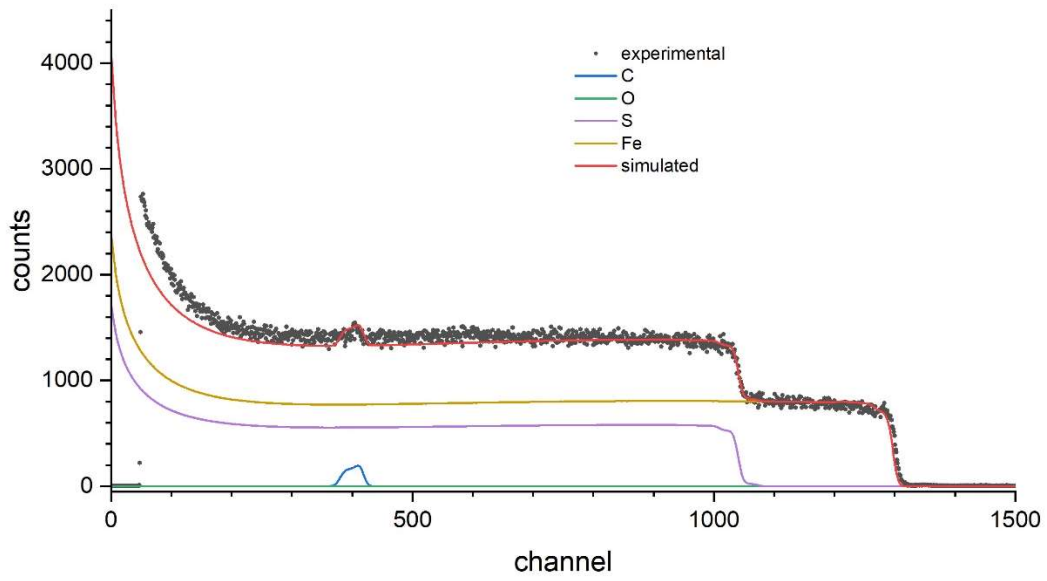


Fig. S7. RBS data and fitting results for mineral pyrite obtained under C-resonance conditions.

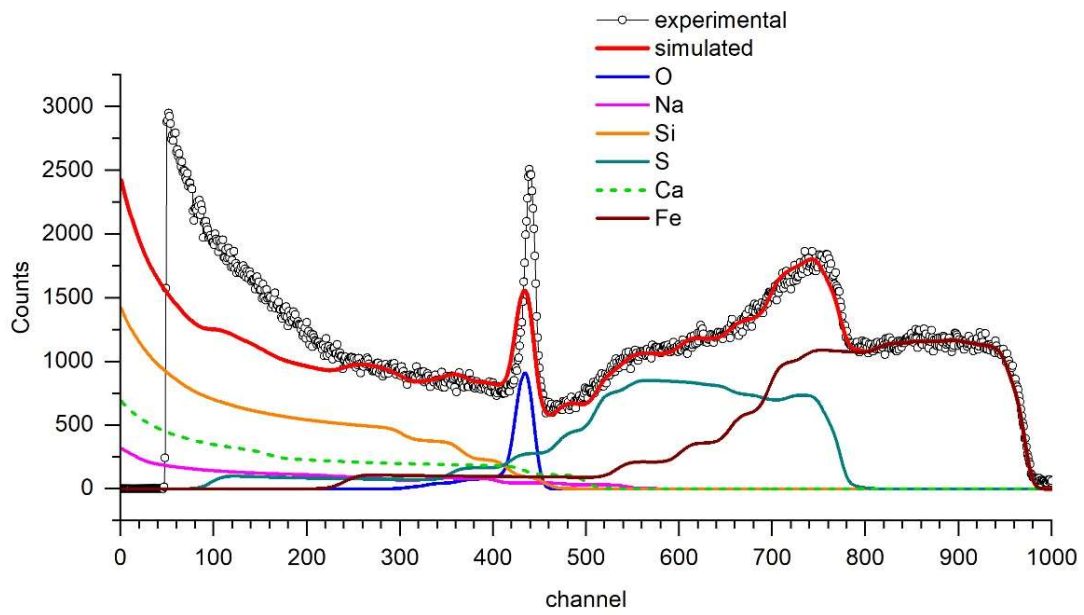


Fig. S8. RBS data and fitting results for thin film FeS<sub>2</sub> obtained under O-resonance conditions.

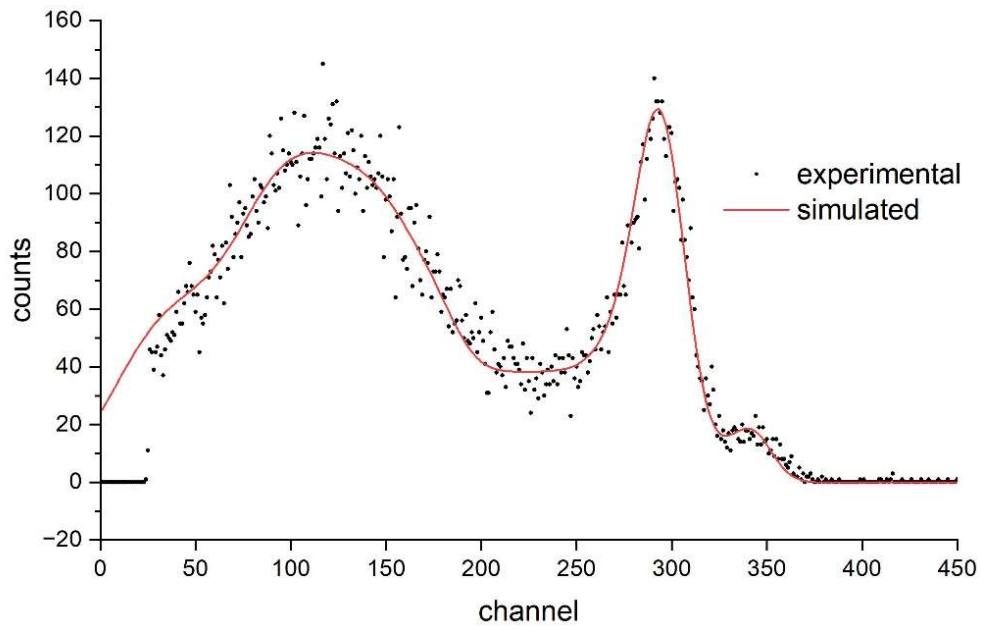


Fig. S9. ERDA data and fitting results for FeS<sub>2</sub> thin film obtained under O-resonance conditions.

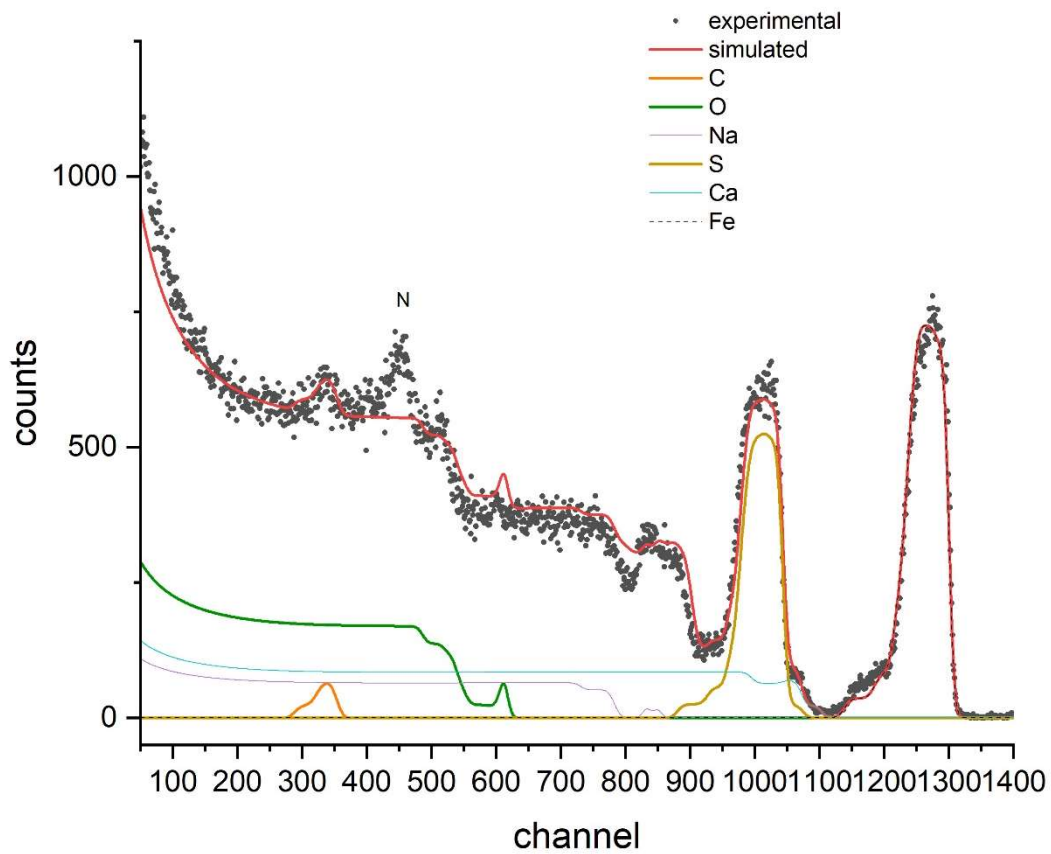


Fig. S10. RBS data and fitting results for FeS<sub>2</sub> thin film obtained under C-resonance conditions.

### 3. X-ray Photoelectron Spectrometry (XPS) of thin-film FeS<sub>2</sub>

Table S1. The binding energies of various elements used for fitting of XPS spectra

Band		Bond energy (eV)	Possible chemical structure	References
Fe 2p <sub>3/2</sub>	Fe1	706.7 ± 0.2	Fe(II)(FeS <sub>2</sub> ) surface states	[1-5]
	Fe2	708.7 ± 0.3	FeS, FeOOH, FeO	[1, 4]
	Fe3	711.8 ± 0.5	αFe <sub>2</sub> O <sub>3</sub> , αFeOOH	[1, 2, 6]
S 2p	S1	160.8 ± 0.6	S <sup>2-</sup> (FeS)	[1, 4, 7-9]
	S2	162.1 ± 0.1	S <sub>2</sub> <sup>2-</sup> (FeS <sub>2</sub> )	[1-10]
	S3	164.0 ± 0.3	S <sup>0</sup> , S <sub>n</sub> <sup>2-</sup> , Fe <sub>1-x</sub> S <sub>2</sub>	[1-4, 6, 7, 10]
	S4	168.2 ± 0.2	SO <sub>4</sub> <sup>2-</sup> (Fe <sub>2</sub> (SO <sub>4</sub> ) <sub>3</sub> , FeSO <sub>4</sub> 7H <sub>2</sub> O)	[2-5, 8]
O 1s	O1	529.7 ± 0.1	Fe <sub>x</sub> O <sub>y</sub>	
	O2	531.7 ± 0.1	O-H	
	O3	533.4 ± 0.1	H <sub>2</sub> O, COH	
C 1s	C1	287.3 ± 0.1	C=O	
	C2	284.8 ± 0.1	C-C, C-H	
	C3	290.4 ± 0.1	carbonates	

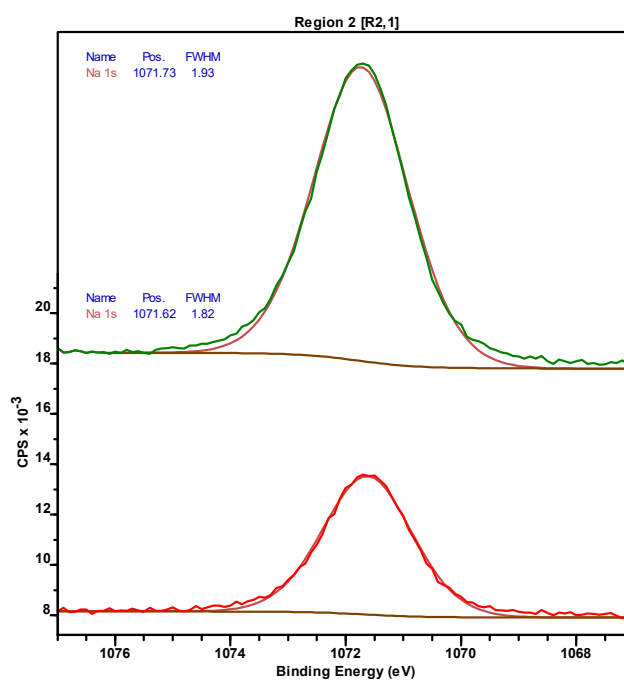


Fig. S11. XPS spectra of Na 1s: low part – before sputtering, upper part – after sputtering

## 4. Mechanically-Stimulated Gas Emission Mass Spectrometry (MSGE-MS)

Table S2. Assignment of the mass-spectrometry channels to possible ions

BP	$m/z$	Possible precursors and corresponding ionic fragments						
		$C_xH_y$	$SO_x$	$H_2S$	$CO_x$	$COS$	$CS_2$	$S_x$
$\alpha$	12	$C^+$			$C^+$		$C^+$	
$\beta$	13	$CH^+$						
	14	$CH_2^+$						
	15	$CH_3^+$						
	16	$CH_4^+$	$O^+$		$O^+$	$O^+$		
	27	$C_2H_5^+$						
	28	$C_2H_4^+$			$CO^+$	$CO^+$		
	29	$C_2H_5^+$						
	30	$C_2H_6^+$						
	32		$S^+$	$S^+$		$S^+$	$S^+$	$S^+$
	33			$HS^+$				
	34			$H_2S^+$				
	44				$CO_2^+$	$CS^+$	$CS^+$	
48		$SO^+$						
$\xi$	60					$COS^+$		
$\beta$	64		$SO_2^+$				$S_2^+$	
$\delta$	76					$CS_2^+$		
$\beta$	96						$S_3^+$	



## 5. Electron stimulated desorption (ESD)

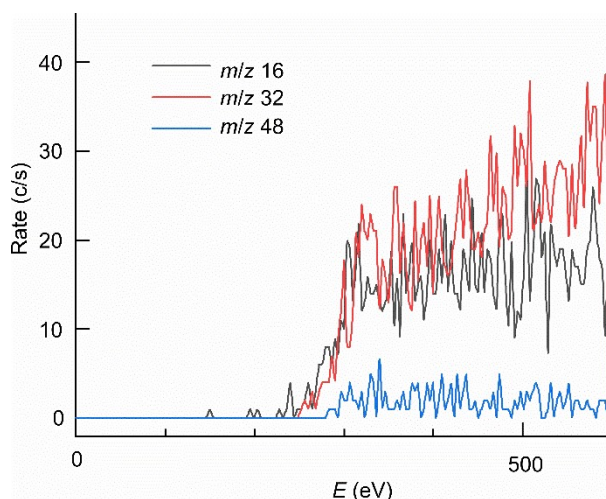


Fig. S12. The ion currents for ion emission at various  $m/z$  ratios as function of incident electron energy.

## 6. Thermal programmed desorption

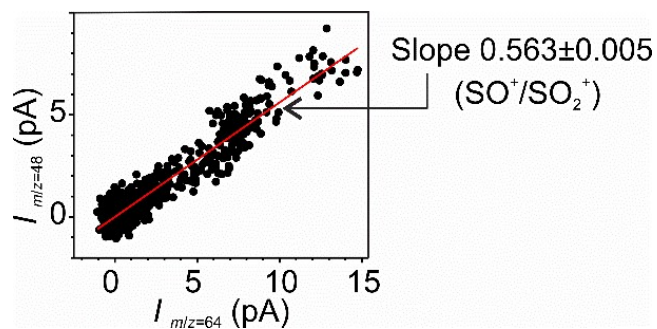
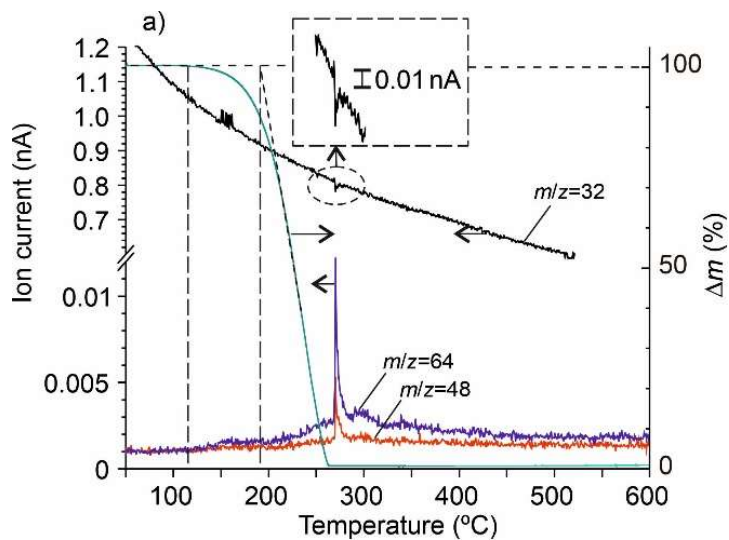


Fig. S13. Correlation between the mass-spectrometer signals at  $m/z$  48 and 64 measured in the TPD experiments using a  $FeS_2$  thin film at  $20^\circ C/min$  in Ar.



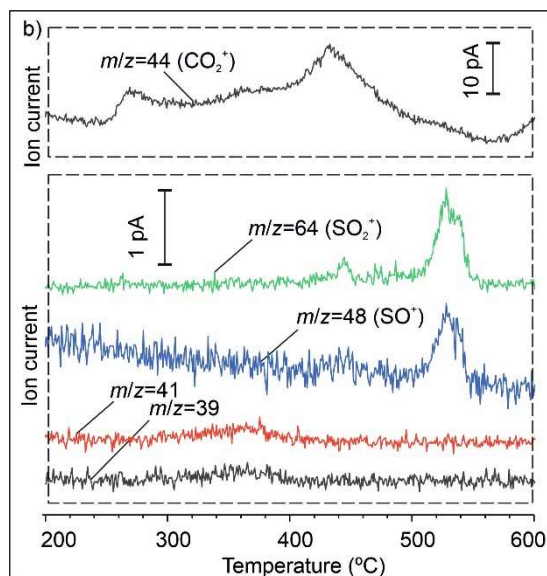


Fig. S14. a) TGA-MS results for elemental sulfur under linear heating rate 10 °C/min under Ar;  
 b) dry air flow, 10 °C/min

Under a dry air flow, the peak of  $\text{SO}_2$  thermal desorption shifted to higher temperatures. A broad peak at  $m/z$  44, which was assigned to  $\text{CO}_2$  and C3 hydrocarbons, was observed in the temperature range of 245 – 555 °C. The assignment of  $m/z$  44 to  $\text{CO}_2^+/\text{C}_3\text{H}_8^+$  instead of  $\text{CS}^+$  was supported by a synchronous but weak emission at  $m/z$  22 ( $\text{CO}_2^{++}$ ), 39 ( $\text{C}_3\text{H}_3^+$ ) and 41 ( $\text{C}_3\text{H}_5^+$ ) as well as the absence of emission at  $m/z$  32 ( $\text{S}^+$ ), 60 ( $\text{COS}^+$ ) and 76 ( $\text{CS}_2^+$ ).

## 7. Optical image and FTIR analysis of Mechanically Affected Zones (MAZ)

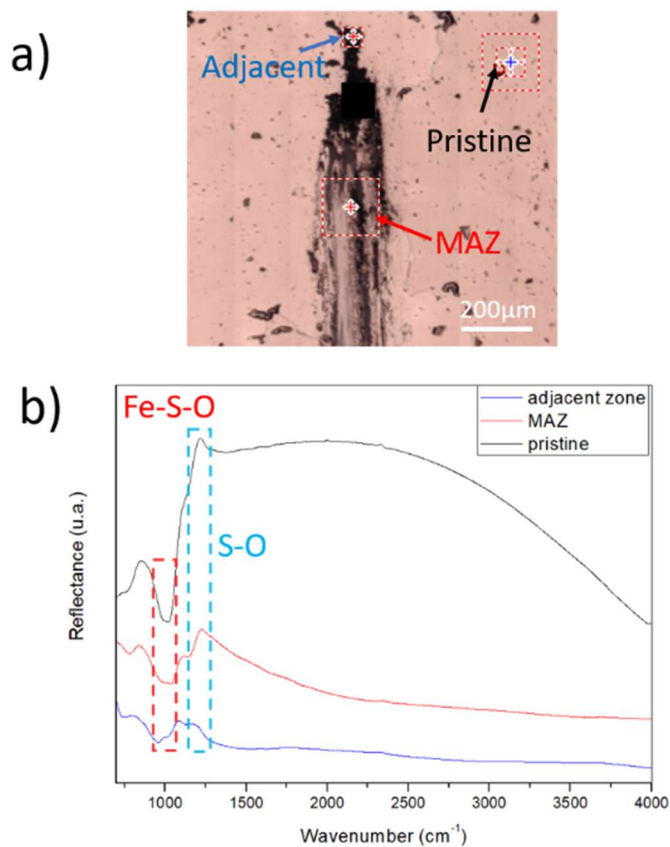


Fig. S15. a) Optical image of the sample surface after MSGE tests; b) the Infrared micro-reflectance spectra of non-affected region (pristine), mechanically affected zone (MAZ), adjacent zone. The band at 812 and 1330  $\text{cm}^{-1}$  corresponds to asymmetric stretching of sulfur functional groups such as S-O. [11-16]

## 8. Nanoindentation

The elastic modulus was calculated following:

$$E_r = \frac{\sqrt{\pi}}{2\beta} \frac{S}{\sqrt{A}}, \quad (1)$$

where

$$\frac{1}{E_r} = \frac{(1-\nu^2)}{E} + \frac{(1-\nu_i^2)}{E_i}, \quad (2)$$

$A$  is the projected contact area between indenter and sample,  $S$  is the contact stiffness,  $\beta$  is a correction factor ( $\beta = 1.034$  for a Berkovich indenter) and  $E_r$  is the reduced elastic modulus accounting for the combined effect of sample and indenter. Equation 2 relates  $E_r$  to the elastic modulus and Poisson's ratio of the sample,  $E$  and  $\nu$  respectively, and those of the indenter,  $E_i$  and  $\nu_i$  respectively. It is assumed that  $E_i = 1141$  GPa  $\nu_i = 0.07$  and  $\nu = 0.15$ . The  $A$  function was calibrated for small penetration depths against a fused silica standard and such calibration yielded constant  $E$  values for  $h \geq 20$  nm.

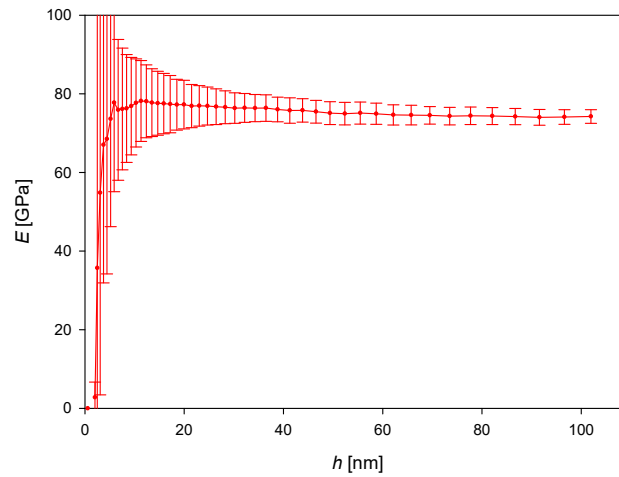


Figure S16. Young modulus as a function of indentation depth, for a fused silica standard.

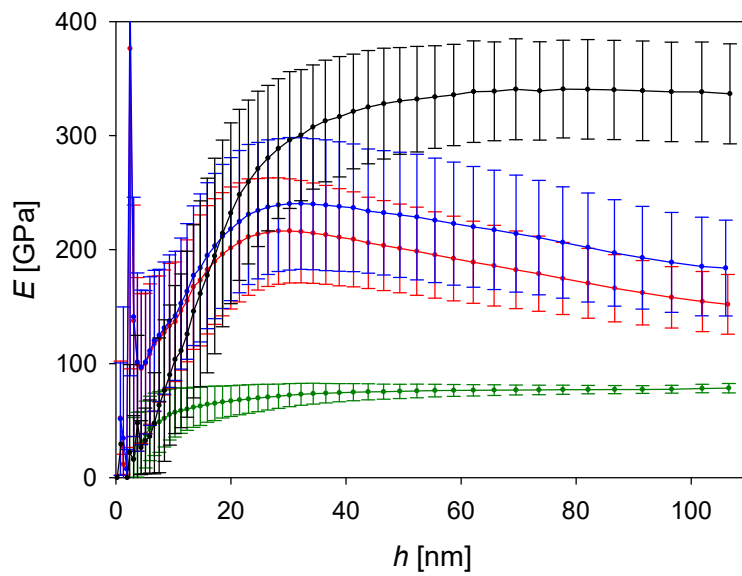


Figure S17. Indentation  $E$  values as a function of indenter displacement for: (●) natural pyrite; (●) polycrystalline pyrite thin film deposited on a glass substrate; (●) polycrystalline pyrite thin film deposited on a glass substrate, after correction for substrate contribution [8]; (●) glass substrate.

## 9. Model of heat dissipation at sliding interface

Approximate solution for flash temperature (circular contact on half-space):

$$\Delta T_{\max} = \frac{2 r \mu \sigma V}{\sqrt{\pi} (\lambda_1 + \sqrt{1 + Pe_1} + \lambda_2)}$$

where  $r$  is the size of the contact zone along the direction of sliding,  $\mu$  is the friction coefficient,  $\sigma$  is the mean contact pressure,  $V$  is the sliding velocity,  $\lambda$  is the thermal conductivity,  $Pe_1$  is the Peclet number for the flat sample:

$$Pe_1 = \frac{V r \rho C p_1}{2 \lambda_1}$$

Where  $\rho_1$  is the material density and  $Cp_1$  is the heat capacity of the flat sample.

Subscripts 1 and 2 refer to the flat sample and the pin, correspondingly.

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